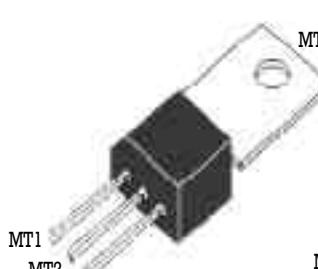
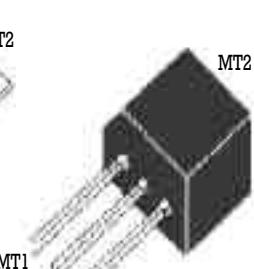


LOGIC LEVEL TRIAC

TO202-1 (E) 	TO202-3 (F) 	On-State Current 4 Amp Gate Trigger Current < 5 mA to < 10 mA
		Off-State Voltage 200 V ÷ 600 V
		<p>This series of TRIACs uses a high performance PNPN technology.</p> <p>These parts are intended for general purpose AC switching applications with highly inductive loads.</p>

Absolute Maximum Ratings, according to IEC publication No. 134

SYMBOL	PARAMETER	CONDITIONS	Min.	Max.	Unit
$I_{T(RMS)}$	RMS On-state Current	All Conduction Angle, $T_c = 110^\circ C$	4		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 60 Hz	21		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 50 Hz	20		A
I^2t	Fusing Current	$t_p = 10 \text{ ms}$, Half Cycle	2.2		A^2s
I_{GM}	Peak Gate Current	20 μs max.		1.2	A
P_{GM}	Peak Gate Dissipation	20 μs max.		2	W
$P_{G(AV)}$	Gate Dissipation	20 ms max.		0.2	W
di/dt	Critical rate of rise of on-state current	$I_G = 2 \times I_{GT}$ Tr = 200 ns, F = 120 Hz $T_j = 125^\circ C$	20		$A/\mu s$
T_j	Operating Temperature		-40	+125	$^\circ C$
T_{stg}	Storage Temperature		-40	+150	$^\circ C$
T_{sld}	Soldering Temperature	1.6 mm from case, 10s max.		260	$^\circ C$

SYMBOL	PARAMETER	CONDITIONS	VOLTAGE			Unit
			B	D	M	
V_{DRM} V_{RRM}	Repetitive Peak Off State Voltage	$R_{GK} = 1 K$	200	400	600	V

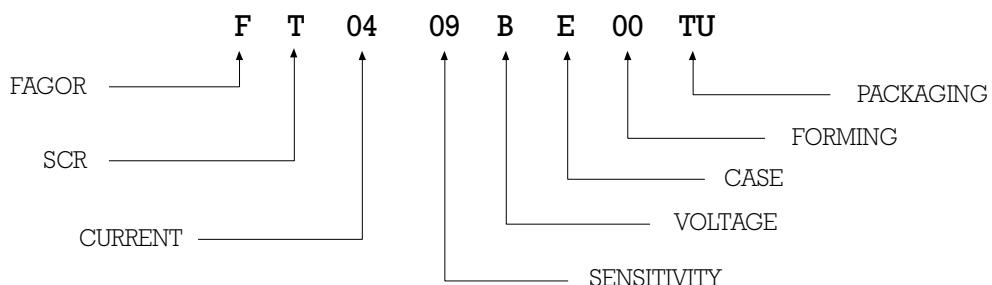
LOGIC LEVEL TRIAC

Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	Quadrant		SENSITIVITY		Unit
					05	09	
I_{GT}	Gate Trigger Current	$V_D = 12 \text{ V}_{DC}, R_L = 30 \Omega, T_j = 25^\circ\text{C}$	Q1÷Q3 Q4	MAX MAX	5	10	mA
					5	10	mA
I_{DRM} / I_{RRM}	Off-State Leakage Current	$V_D = V_{DRM}, T_j = 125^\circ\text{C}$ $V_R = V_{RRM}, T_j = 25^\circ\text{C}$		MAX MAX	0.5		mA
					5		μA
V_{to}	Threshold Voltage	$T_j = 125^\circ\text{C}$		MAX	0.95		V
R_d	Dynamic Resistance	$T_j = 125^\circ\text{C}$		MAX	180		m
V_{TM}^*	On-state Voltage	$I_T = 5.5 \text{ Amp}, t_p = 380 \mu\text{s}, T_j = 25^\circ\text{C}$		MAX	2		V
V_{GT}	Gate Trigger Voltage	$V_D = 12 \text{ V}_{DC}, R_L = 30 \Omega, T_j = 25^\circ\text{C}$	Q1÷Q4	MAX	1.3		V
V_{GD}	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3\text{K}, T_j = 125^\circ\text{C}$	Q1÷Q4	MIN	0.2		V
I_H^*	Holding Current	$I_T = 50 \text{ mA}, T_j = 25^\circ\text{C}$		MAX	7	10	mA
I_L	Latching Current	$I_G = 1.2 I_{GT}, T_j = 25^\circ\text{C}$	Q1,Q3,Q4 Q2	MAX MAX	10	15	mA
					15	25	
dv / dt^*	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, \text{ Gate open}$ $T_j = 125^\circ\text{C}$		MIN	20	100	V/ μs
$(dv/dt)c^*$	Critical rise rate of commutating off-state Voltage	$(di/dt)c = 1.8 \text{ A/ms}$ $T_j = 110^\circ\text{C}$		MIN	1	2	V/ μs
$R_{th(j-l)}$	Thermal Resistance Junction-Leads for AC					15	$^\circ\text{C/W}$
$R_{th(j-a)}$	Thermal Resistance Junction-Ambient					100	$^\circ\text{C/W}$

(*) For either polarity of electrode MT2 voltage with reference to electrode MT1.

PART NUMBER INFORMATION



LOGIC LEVEL TRIAC

Fig. 1: Maximum average power dissipation versus RMS on-state current (full cycle)

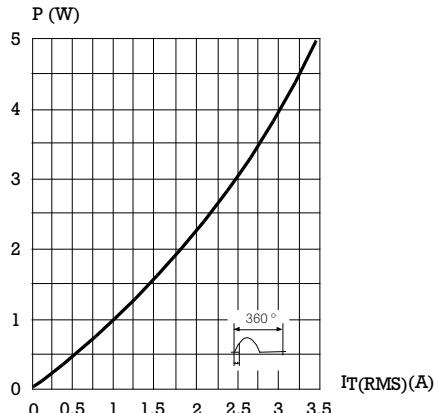


Fig. 3: Relative variation of thermal impedance junction to ambient versus pulse duration.

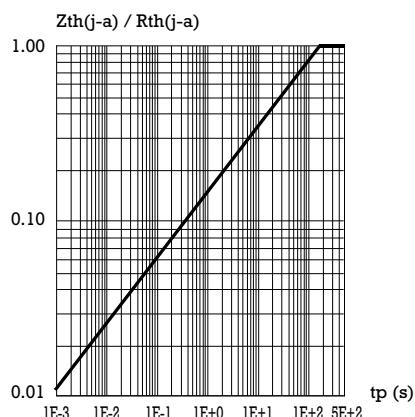


Fig. 5: Non repetitive surge peak on-state current versus number of cycles.

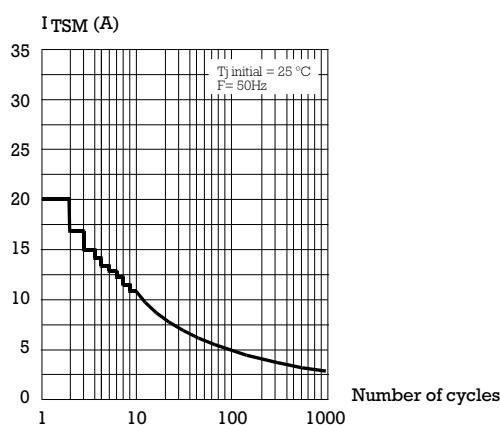


Fig. 2: RMS on-state current versus ambient temperature (full cycle)

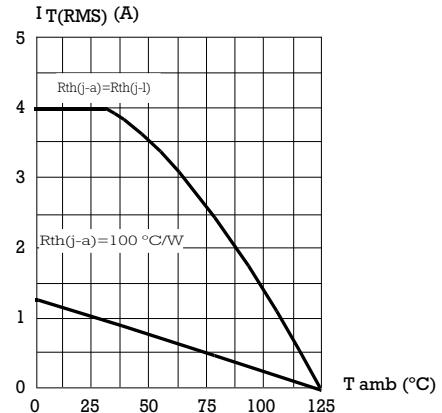


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

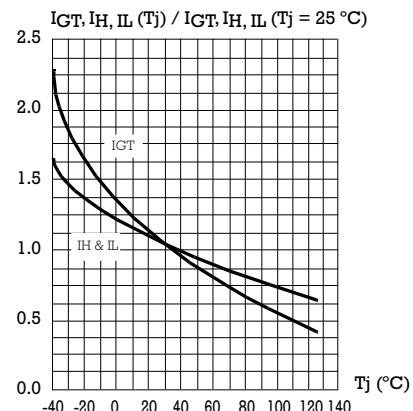
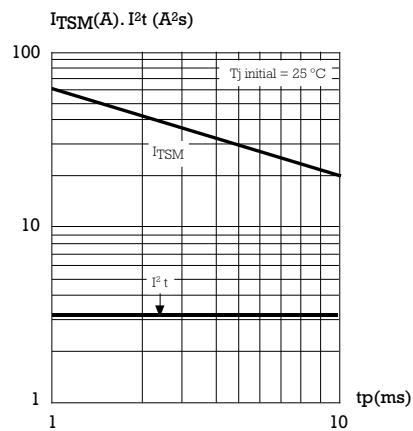
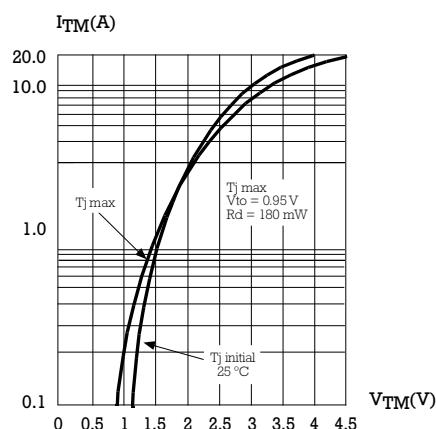


Fig. 6: Non repetitive surge peak on-state current for a sinusoidal pulse with width: tp = 10 ms, and corresponding value of I²t.



LOGIC LEVEL TRIAC

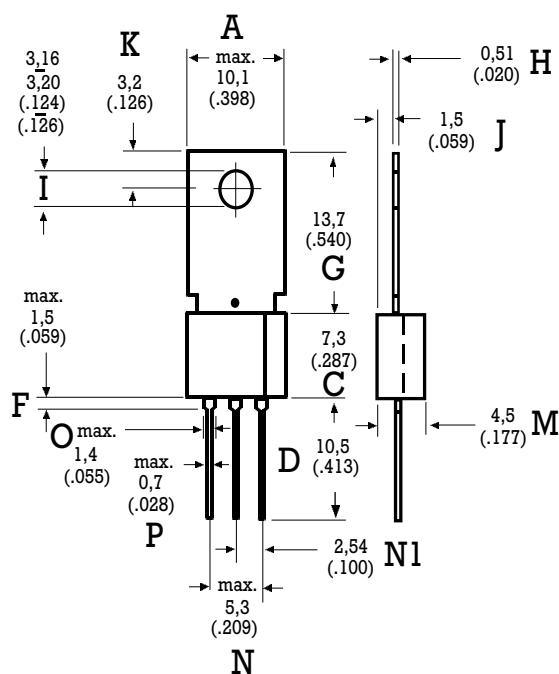
Fig. 7: On-state characteristics (maximum values)



PACKAGE MECHANICAL DATA

TO 202-1 TO 202-3

TO 202-1



TO 202-3

